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▶ To cite this version:

Baojie Li, Claude Delpha, Demba Diallo, A. Migan-Dubois. Application of Artificial Neural Networks to photovoltaic fault detection and diagnosis: A review. Renewable and Sustainable Energy Reviews, 2020, 138, pp.110512. 10.1016/j.rser.2020.110512. hal-03087601

HAL Id: hal-03087601 https://centralesupelec.hal.science/hal-03087601

Submitted on 4 Nov 2021

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Application of Artificial Neural Networks to Photovoltaic Fault Detection

and Diagnosis: A review

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Abstract: The rapid development of photovoltaic (PV) technology and the growing number and size of PV power plants require increasingly efficient and intelligent health monitoring strategies to ensure reliable operation and high energy availability. Among the various techniques, Artificial Neural Network (ANN) has exhibited the functional capacity to perform the identification and classification of PV faults. In the present review, a systematic study on the application of ANN and hybridized ANN models for PV fault detection and diagnosis (FDD) is conducted. For each application, the targeted PV faults, the detectable faults, the type and amount of data used, the model configuration and the FDD performance are extracted, and analyzed. The main trends, challenges and prospects for the application of ANN for PV FDD are extracted and presented.

Keywords: photovoltaic; artificial neural network; fault detection; fault classification; machine learning; deep learning;

Highlights:

- Applications of ANN technique and hybrid application for PV FDD are summarized.
- Detectable PV faults with ANN technique and diagnosis performance are investigated.
- Reported public PV database of 1D data and 2D images are summarized.
- Common trends on the selection and the configuration of model are identified.
- Challenges and prospects on PV FDD using ANN techniques are presented.

1.Introduction

In recent decades, photovoltaic (PV) technology has experienced an accelerated development as one of the promising renewable energy sources relying on various merits, including pollution-free, safe energy generation, noiseless operation and decreasing installation costs [1–3]. Nevertheless, due to the outdoor operating conditions (random variations of environmental conditions) and the potential damages involved in the manufacturing, transportation or installation [4], various PV faults may accordingly arise up and lead to different levels of degradation, power loss or even fire hazard [5,6]. It is reported that the power loss in the UK could reach 18.9% in one year [7], which is found mainly due to the sustained inverter failure and shading fault. As a consequence, it is relevant to conduct efficient health monitoring for PV power plants to ensure the reliability and durability of energy production.

Typical PV fault detection and diagnosis (FDD) strategies can be broadly classified into two categories, visual inspection and automatic fault analysis. The automatic ones could be realized via various methodologies, where the most popular ones include model-based residual analysis and data-driven methods. For the latter one, several kinds of data are commonly used, like electrical measurements, environmental data or images of PV panels. These data-driven analyses can be done with different techniques, such as statistical methods or machine learning technology (MLT) [8]. Compared to others, MLT is competent and proficient to deal with complex and non-linear problems [9].

AC Alternating Current ID, 2D I Dimension, 2 Dimension BPD Bypass diode ANN Anfficial Neural Network DC Diet Current ART Adaptive Resonance Theory EL Electroluminescence BP Back Propagation FF Ground Fault Deep Belief Network IGBT Insulated Gate Biplan Transistor Darcon Convolutional Neural Network IGBT Insulated Gate Biplan Transistor DNN Deep Belief Network LLF Line-to-ine fault DN Deep Maria Network LLF Line-to-ine fault DT Decision Tree mack CO Open Circuit DWT Discrete Wavelet Transform MPP(T) Maintrystalline Silicon FD Fault Detection and Diagnosis PID Potential Induced Degradation FL Fuzzy Logic PS Partial Shading GA Genetic Algorithm PV Photovoltaic GA Genetic Algorithm Stress Neighbors C GLCM Gray Lavel Co-currence M	Nomenclature		Photovoltaic	related terminology
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LRMRLow Rank Matrix Recovery Ep RMSE of parameter identificationMSEMean Squared Error $fval$ Optimal fitness value of I-V curveMLPMulti-layer Perception G Solar irradiance (W/m ²)MLTMachine Learning Technique I Output current (A)MRAMulti Resolution Analysis I_{load} Load current (A)MSDPMultisate Data Processing I_{load} Load current (A)NAGNesterov Accelerated Gradient I_{MPP} Current at MPP (A)NMSNelder-Mead Simplex I_{ph} Photocurrent (A)NNNeural Network I_{sc} Short circuit current (A)NNNeural Network I_{sc} Short circuit current (A)PCAPrincipal Component Analysis n Ideality factorPSOParticle Swarm Optimization Np Number of ANN parametersPNNProbabilistic Neural Network PR Power ratio (%)Restricted Boltzmann Machine R_{S} Scrise resistance (Q)RBFRadical Basis Function R_{s} Scrise resistance (Q)RMSERoot Mean Squared Error T_{A} Ambient temperature (°C)SASimulated Annealing T_M Module temperature (°C)SASimulated Annealing T_M Module temperature (°C)RSFRadient Network T_A Ambient temperature (°C)SASimulated Annealing T_M Module temperature (°C)SASimulated Annealing T_M Module temperature (°C) <td>LM</td> <td>Levenberg-Marquardt</td> <td>C_R</td> <td>DMCE of non-model identification</td>	LM	Levenberg-Marquardt	C_R	DMCE of non-model identification
MSEMean Squared Error <i>Jolt</i> Optimal Indexs Value Of 1-V CurveMLPMulti-layer Perception G Solar irradiance (W/m ²)MLTMachine Learning Technique I Output current (A)MRAMulti Resolution Analysis I_{acc} AC side current (A)MSDPMultistate Data Processing I_{loud} Load current (V)NAGNesterov Accelerated Gradient I_{MPP} Current at MPP (A)NMSNelder-Mead Simplex I_{ph} Photocurrent (A)NNNeural Network I_{sc} Short circuit current (A)PCAPrincipal Component Analysis n Ideality factorPSOParticle Swarm Optimization Np Number of ANN parametersPNNProbabilistic Neural Network P_{RPP} Power ratio (%)ResNetDeep Residual Network R_{ss} Series resistance (Ω)RBFRadical Basis Function R_s Series resistance (Ω)RBMRestricted Boltzmann Machine T_A Ambient temperature (%C)RNNRecurrent Neural Network T_A Ambient temperature (%C)SGScaled Conjugate Gradient V_{AC} Inverter voltage (V)SGDStochastic Gradient Descent V_{AC} Inverter voltage (V)SGDStochastic Gradient Descent V_{AC} Inverter voltage (V)SVMShalpov Vector Machine V_{AC} Inverter voltage (V)SVMShalpov Neural Network V_{AC} Inverter voltage (V)SVMShalpov Neural Network	LRMR	Low Rank Matrix Recovery	Ep	RMISE of parameter identification
MLPMulti-layer PerceptionGSolar irradiance (W/m²)MLTMachine Learning TechniqueIOutput current (A)MRAMulti Resolution Analysis I_{AC} AC side current (A)MSDPMultistate Data Processing I_{load} Load current (V)NAGNesterov Accelerated Gradient I_{MPP} Current at MPP (A)NMSNelder-Mead Simplex I_{ph} Photocurrent (A)NNNeural Network I_{SC} Short circuit current (A)PCAPrincipal Component AnalysisnIdeality factorPSOParticle Swarm Optimization Np Number of ANN parametersPNNProbabilistic Neural Network P_{RPP} Power at MPP (W)ReLURectified Linear Unit PR Power ratio (%)ResNetDeep Residual Network R_{I-MPP} Ratio of current at MPP (%)RBFRadical Basis Function R_s Series resistance (\Omega)RMSERoot Mean Squared Error R_{Voc} Ratio of voltage at MPPRNNRecurrent Neural Network T_A Ambient temperature (°C)SASimulated Annealing T_M Module temperature (°C)SGDStochastic Gradient Descent V_{AC} Inverter voltage (V)SGDStochastic Gradient Descent V_{AC} Inverter voltage (V)SVMSupport Vector Machine V_{AC} Inverter voltage (V)SVMSupport Vector Machine V_{AC} Inverter voltage (V)SVMSupport Vector Machine V_{AC}	MSE	Mean Squared Error	jvai	Optimal fitness value of I-v curve
MLTMachine Learning TechniqueIOutput current (A)MRAMulti Resolution Analysis I_{AC} AC side current (A)MSDPMultistate Data Processing I_{noal} Load current (V)NAGNesterov Accelerated Gradient I_{MPP} Current at MPP (A)NMSNelder-Mead Simplex I_{ph} Photocurrent (A)NNNeural Network I_{SC} Short circuit current (A)PCAPrincipal Component Analysis n Ideality factorPSOParticle Swarm Optimization Np Number of ANN parametersPNNProbabilistic Neural Network PR Power ratio (%)ResNetDeep Residual Network R_{LMPP} Ratio of current at MPP (%)ResNetDeep Residual Network R_{s} Series resistance (Ω)RBFRadical Basis Function R_{VMPP} Ratio of voltage at MPPRMSERoot Mean Squared Error T_A Ambient temperature (°C)SASimulated Annealing T_M Module temperature (°C)SASimulated Annealing T_M Module temperature (°C)SGDStochastic Gradient V_{AC} Inverter voltage (V)SVMSupport Vector Machine V_{ooc} Open circuit voltage (V)SVMSupport Vector Machine V_{ooc} Open circuit voltage (V)VSVMSupport Vector Machine V_{ooc} Open circuit voltage (V)VSVMSupport Vector Machine V_{ooc} Open circuit voltage (V)VNNWavelet neural network <td< td=""><td>MLP</td><td>Multi-layer Perception</td><td>G</td><td>Solar irradiance (W/m²)</td></td<>	MLP	Multi-layer Perception	G	Solar irradiance (W/m ²)
MRAMulti Resolution Analysis I_{AC} AC side current (A)MSDPMultistate Data Processing I_{load} Load current (V)NAGNesterov Accelerated Gradient I_{MPP} Current at MPP (A)NMSNelder-Mead Simplex I_{ph} Photocurrent (A)NNNeural Network I_{SC} Short circuit current (A)PCAPrincipal Component Analysis n Ideality factorPSOParticle Swarm Optimization Np Number of ANN parametersPSOParticle Swarm Optimization PR Power at MPP (W)PNNProbabilistic Neural Network P_{MPP} Power at MPP (W)PRELURectified Linear Unit PR Power ratio (%)ResNetDeep Residual Network R_{S} Series resistance (Ω)RBFRadical Basis Function R_S Series resistance (Ω)RMSERoot Mean Squared Error R_{Vare} Ratio of open circuit voltage (%)RNNRecurrent Neural Network T_A Ambient temperature ($^{\circ}$ C)SASimulated Annealing V_{MPP} Ac dide ubget (V)SGDStochastic Gradient V_{AC} Inverter voltage (V)SNNShallow Neural Network V_{MPP} Ac dide voltage (V)SNNShallow Neural Network V_{MPP} <td>MLT</td> <td>Machine Learning Technique</td> <td>I</td> <td>Output current (A)</td>	MLT	Machine Learning Technique	I	Output current (A)
MSDPMultistate Data Processing I_{load} Load current (V)NAGNesterov Accelerated Gradient I_{MPP} Current at MPP (A)NMSNelder-Mead Simplex I_{ph} Photoccurrent (A)NNNeural Network I_{SC} Short circuit current (A)NNNeural Network I_{SC} Short circuit current (A)PCAPrincipal Component Analysis n Ideality factorPSOParticle Swarm Optimization Np Number of ANN parametersPNNProbabilistic Neural Network PR Power at MPP (W)ReLURectified Linear Unit R_{R} Power ratio (%)ResNetDeep Residual Network R_{I-MPP} Ratio of current at MPP (%)RBFRadical Basis Function R_{S} Series resistance (Ω)RBMRestricted Boltzmann Machine R_{Voc} Ratio of optage at MPPRMSERoot Mean Squared Error T_A Ambient temperature (°C)RNNRecurrent Neural Network T_M Module temperature (°C)SASimulated Annealing V Output voltage (V)SGDStochastic Gradient Descent V_{AC} Inverter voltage (V)SNNShallow Neural Network V_{Ioad} Load voltage (V)SNNShallow Neural Network V_{MPP} AC side voltage (V)SNNShallow Neural Network V_{MPP} AC side voltage (V)SNNShallow Neural Network V_{MPP} Ac side voltage (V)SNNShallow Neural Network V_{MPP}	MRA	Multi Resolution Analysis		AC side current (A)
NAGNesterov Accelerated Gradient I_{MPP} Current at MPP (A)NMSNelder-Mead Simplex I_{ph} Photocurrent (A)NNNeural Network I_{SC} Short circuit current (A)PCAPrincipal Component Analysis n Ideality factorPSOParticle Swarm Optimization Np Number of ANN parametersPNNProbabilistic Neural Network P_{MPP} Power at MPP (W)ReLURectified Linear Unit R_{I-MPP} Power ratio (%)ResNetDeep Residual Network R_{S} Series resistance (Ω)RBFRadical Basis Function R_S Series resistance (Ω)RMSERoot Mean Squared Error R_{Vore} Ratio of optage at MPPRMSERoot Mean Squared Error T_M Module temperature (°C)SASimulated Annealing V Output voltage (V)SCGScaled Conjugate Gradient V_{AC} Inverter voltage (V)SNNShallow Neural Network V_{MPP} AC side voltage (V)SNNShallow Neural Network V_{occ} Opto circuit voltage (V)SVMSupport Vector Machine V_{occ} Opto circuit voltage (V)SVMSupport Vector Machine V_{occ} Opto circuit voltage (V)transformtransform V_{ocd} Load voltage (V)SVMSupport Vector Machine V_{occ} Opto circuit voltage (V)transformtransform V_{MND} Wind direction	MSDP	Multistate Data Processing	Iload	Load current (V)
NMSNelder-Mead Simplex I_{ph} Photocurrent (A)NNNeural Network I_{SC} Short circuit current (A)PCAPrincipal Component Analysis n Ideality factorPSOParticle Swarm Optimization Np Number of ANN parametersPNNProbabilistic Neural Network P_{MPP} Power at MPP (W)PNNBrobabilistic Neural Network PR Power ratio (%)ReLURectified Linear Unit PR Power ratio of current at MPP (%)ResNetDeep Residual Network R_{IMPP} Ratio of ourrent at MPP (%)RBFRadical Basis Function R_S Series resistance (Ω)RBMRestricted Boltzmann Machine R_{VMPP} Ratio of voltage at MPPRMSERoot Mean Squared Error T_A Ambient temperature (°C)RNNRecurrent Neural Network T_A Module temperature (°C)SASimulated Annealing V_{MC} Inverter voltage (V)SGDStochastic Gradient V_{AC} Inverter voltage (V)SNNShallow Neural Network V_{MPP} AC side voltage (V)SVMSupport Vector Machine V_{load} Load voltage (V)SVMSupport Vector Machine V_{oc} Open circuit voltage (V) V_{NNN} Wavelet neural network V_{RC} Open circuit voltage (V) V_{NND} $V_{avelet neural network$ V_{NRD} Wind direction	NAG	Nesterov Accelerated Gradient	I_{MPP}	Current at MPP (A)
NNNeural Network I_{SC} Short circuit current (A)PCAPrincipal Component Analysis n Ideality factorPSOParticle Swarm Optimization Np Number of ANN parametersPNNProbabilistic Neural Network P_{MPP} Power at MPP (W)ReLURectified Linear Unit PR Power ratio (%)ResNetDeep Residual Network R_{I-MPP} Ratio of current at MPP (%)RBFRadical Basis Function R_S Series resistance (Ω)RBMRestricted Boltzmann Machine R_{Vocc} Ratio of voltage at MPPRMSERoot Mean Squared Error T_A Ambient temperature (°C)RNNRecurrent Neural Network T_A Ambient temperature (°C)SGGScaled Conjugate Gradient V Output voltage (V)SGDStochastic Gradient Descent V_{AC} Inverter voltage (V)SNNShallow Neural Network V_{load} Load voltage (V)SVMSupport Vector Machine V_{occ} Open circuit voltage (V)SVMSupport Vector Machine V_{occ} Open circuit voltage (V)VMNWavelet neural network V_{occ} Open circuit voltage (V)WNNWavelet neural network V_{occ} Open circuit voltage (V)WNNWavelet neural network V_{add} Load voltage (V)SUMSupport Vector Machine V_{occ} Open circuit voltage (V) V_{IND} Wind speed (m/s) W_{IND} Wind direction	NMS	Nelder-Mead Simplex	I_{ph}	Photocurrent (A)
PCAPrincipal Component AnalysisnIdeality factorPSOParticle Swarm Optimization Np Number of ANN parametersPNNProbabilistic Neural Network P_{MPP} Power at MPP (W)ReLURectified Linear Unit PR Power ratio (%)ResNetDeep Residual Network R_{I-MPP} Ratio of current at MPP (%)RBFRadical Basis Function R_S Series resistance (Ω)RBMRestricted Boltzmann Machine R_{V-MPP} Ratio of open circuit voltage (%)RNNRecurrent Neural Network T_A Ambient temperature (°C)SASimulated Annealing T_M Module temperature (°C)SCGScaled Conjugate Gradient V_{AC} Inverter voltage (V)SNNShallow Neural Network V_{MPP} AC side voltage (V)SVMSupport Vector Machine V_{load} Load voltage (V)SVMSupport Vector Machine V_{load} Load voltage (V)SVMWavelet neural network V_{RC} Open circuit voltage (V)SVMShallow Neural Network V_{load} Load voltage (V)SVMSupport Vector Machine V_{load} Load voltage (V) t -SNE t -Distributed Stochastic Neighbor Embedding V_{OC} Open circuit voltage (V) t -SNE t -Distributed Stochastic Neighbor Embedding V_{MPD} Wind direction WNN Wavelet neural network W_{MND} Wind direction	NN	Neural Network	I_{SC}	Short circuit current (A)
PSOParticle Swarm Optimization Np Number of ANN parametersPNNProbabilistic Neural Network P_{MPP} Power at MPP (W)ReLURectified Linear Unit PR Power ratio (%)ResNetDeep Residual Network R_{LMPP} Ratio of current at MPP (%)RBFRadical Basis Function R_S Series resistance (Ω)RBMRestricted Boltzmann Machine R_{VMPP} Ratio of voltage at MPPRMSERoot Mean Squared Error T_A Ambient temperature (°C)RNNRecurrent Neural Network T_A Ambient temperature (°C)SASimulated Annealing V Output voltage (V)SCGScaled Conjugate Gradient V_{AC} Inverter voltage (V)SNNShallow Neural Network V_{MPP} AC side voltage (V)SVMSupport Vector Machine V_{load} Load voltage (V)trSNsupport Vector Machine V_{OC} Open circuit voltage (V)trSNSupport Vector Machine V_{load} Load voltage (V)trSNWNNWavelet neural network VR Voltage ratio (%)WNNWavelet neural network VR Voltage ratio (%)WNNWavelet neural network VR Voltage ratio (%)Wind directionWind by evel (m/s)Wind direction	PCA	Principal Component Analysis	n	Ideality factor
PNNProbabilistic Neural Network P_{MPP} Power at MPP (W)ReLURectified Linear Unit PR Power ratio (%)ResNetDeep Residual Network R_{LMPP} Ratio of current at MPP (%)RBFRadical Basis Function R_S Series resistance (Ω)RBMRestricted Boltzmann Machine R_{V-MPP} Ratio of voltage at MPPRMSERoot Mean Squared Error R_{Voc} Ratio of open circuit voltage (%)RNNRecurrent Neural Network T_A Ambient temperature (°C)SASimulated Annealing T_M Module temperature (°C)SCGScaled Conjugate Gradient V_AC Inverter voltage (V)SNNShallow Neural Network V_{MPP} AC side voltage (V)SVMSupport Vector Machine V_{load} Load voltage (V)SVMSupport Vector Machine V_{OC} Open circuit voltage (V)tr.SNEt-Distributed Stochastic Neighbor Embedding V_{OC} Open circuit voltage (V)WNNWavelet neural network VR Voltage ratio (%)Wind speed (m/s) $Wind$ Wind direction	PSO	Particle Swarm Optimization	Np	Number of ANN parameters
ReLURectified Linear Unit PR Power ratio (%)ResNetDeep Residual Network R_{I-MPP} Ratio of current at MPP (%)RBFRadical Basis Function R_s Series resistance (Ω)RBMRestricted Boltzmann Machine R_{V-MPP} Ratio of voltage at MPPRMSERoot Mean Squared Error R_{Voc} Ratio of open circuit voltage (%)RNNRecurrent Neural Network T_A Ambient temperature (°C)SASimulated Annealing V_M Output voltage (V)SGDStochastic Gradient V_{AC} Inverter voltage (V)SNNShallow Neural Network V_{MPP} AC side voltage (V)SVMSupport Vector Machine V_{load} Load voltage (V)SVMSupport Vector Machine V_{OC} Open circuit voltage (V) t -SNE t -Distributed Stochastic Neighbor Embedding V_{OC} Open circuit voltage (V)WNNWavelet neural network V_{R} Voltage ratio (%) $WIND$ Wind speed (m/s) $Wind$ $Wind$	PNN	Probabilistic Neural Network	P_{MPP}	Power at MPP (W)
ResNetDeep Residual Network R_{I-MPP} Ratio of current at MPP (%)RBFRadical Basis Function R_S Series resistance (Ω)RBMRestricted Boltzmann Machine R_{Vac} Ratio of voltage at MPPRMSERoot Mean Squared Error R_{Vac} Ratio of open circuit voltage (%)RNNRecurrent Neural Network T_A Ambient temperature (°C)SASimulated Annealing T_M Module temperature (°C)SGDStochastic Gradient Descent V_{AC} Inverter voltage (V)SNNShallow Neural Network V_{MPP} AC side voltage (V)SVMSupport Vector Machine V_{load} Load voltage (V)F-SNE r -Distributed Stochastic Neighbor Embedding V_{OC} Open circuit voltage (V)WNNWavelet neural network VR Voltage ratio (%)Wind direction V_{WIND} Wind direction	ReLU	Rectified Linear Unit	PR	Power ratio (%)
RestDeep RestrictedDeep Restricted R_{S} Series resistance (Ω)RBFRadical Basis Function R_{S} Series resistance (Ω)RBMRestricted Boltzmann Machine R_{Vac} Ratio of voltage at MPPRMSERoot Mean Squared Error R_{Vac} Ratio of open circuit voltage (%)RNNRecurrent Neural Network T_A Ambient temperature (°C)SASimulated Annealing T_M Module temperature (°C)SCGScaled Conjugate Gradient V Output voltage (V)SGDStochastic Gradient Descent V_{AC} Inverter voltage (V)SNNShallow Neural Network V_{load} Load voltage (V)SVMSupport Vector Machine V_{load} Load voltage (V) t -SNE t -Distributed Stochastic Neighbor Embedding V_{OC} Open circuit voltage (V)WNNWavelet neural network V_{WIND} Wind speed (m/s) d_{WIND} Wind direction d_{WIND}	ResNet	Deep Residual Network	R_{I-MPP}	Ratio of current at MPP (%)
RDTRatioRatio of voltage at MPPRBMRestricted Boltzmann Machine R_{Voc} Ratio of open circuit voltage (%)RMSERoot Mean Squared Error T_A Ambient temperature (°C)RNNRecurrent Neural Network T_A Module temperature (°C)SASimulated Annealing T_M Module temperature (°C)SCGScaled Conjugate Gradient V Output voltage (V)SGDStochastic Gradient Descent V_{AC} Inverter voltage (V)SNNShallow Neural Network V_{MPP} AC side voltage (V)SVMSupport Vector Machine V_{load} Load voltage (V) t -SNE t -Distributed Stochastic Neighbor Embedding V_{OC} Open circuit voltage (V)WNNWavelet neural network VR Voltage ratio (%) W_{NND} Wind speed (m/s) d_{WIND} Wind direction	RBF	Radical Basis Function	R_S	Series resistance (Ω)
RDMRestricted Doftzham Mathine R_{Voc} Ratio of open circuit voltage (%)RMSERoot Mean Squared Error T_A Ambient temperature (°C)RNNRecurrent Neural Network T_A Module temperature (°C)SASimulated Annealing V Output voltage (V)SCGScaled Conjugate Gradient V_Ac Inverter voltage (V)SGDStochastic Gradient Descent V_{AC} Inverter voltage (V)SNNShallow Neural Network V_{MPP} AC side voltage (V)SVMSupport Vector Machine V_{load} Load voltage (V)t-SNEt-Distributed Stochastic Neighbor Embedding Voc Open circuit voltage (V)WNNWavelet neural network V_{WIND} Wind speed (m/s) d_{WIND} Wind direction $Wind direction$	PBM	Radical Dasis Function Restricted Boltzmann Machine	R_{V-MPP}	Ratio of voltage at MPP
RNNRecurrent Neural Network T_A Ambient temperature (°C)SASimulated Annealing T_M Module temperature (°C)SCGScaled Conjugate Gradient V Output voltage (V)SGDStochastic Gradient Descent V_{AC} Inverter voltage (V)SNNShallow Neural Network V_{MPP} AC side voltage (V)SVMSupport Vector Machine V_{load} Load voltage (V)t-SNEt-Distributed Stochastic Neighbor Embedding V_{OC} Open circuit voltage (V)WNNWavelet neural network V_{R} Voltage ratio (%) W_{NND} Wind speed (m/s) d_{WIND} Wind direction	DMSE	Restricted Boltzmann Machine Poot Mean Squared Error	R_{Voc}	Ratio of open circuit voltage (%)
KINNRecurrent Network T_M Module temperature (°C)SASimulated Annealing T_M Module temperature (°C)SCGScaled Conjugate Gradient V Output voltage (V)SGDStochastic Gradient Descent V_{AC} Inverter voltage (V)SNNShallow Neural Network V_{MPP} AC side voltage (V)SVMSupport Vector Machine V_{load} Load voltage (V)t-SNEt-Distributed Stochastic Neighbor Embedding Voc Open circuit voltage (V)WNNWavelet neural network V_{WIND} Wind speed (m/s) d_{WIND} Wind direction	DNN	Root Mean Squared Enor	T_A	Ambient temperature (°C)
SASimulater Americaning V Output voltage (V)SCGScaled Conjugate Gradient V_{AC} Inverter voltage (V)SGDStochastic Gradient Descent V_{AC} Inverter voltage (V)SNNShallow Neural Network V_{MPP} AC side voltage (V)SVMSupport Vector Machine V_{load} Load voltage (V)t-SNEt-Distributed Stochastic Neighbor Embedding V_{OC} Open circuit voltage (V)WNNWavelet neural network V_{WIND} Wind speed (m/s) d_{WIND} Wind direction	KININ S A	Simulated Appealing	T_M	Module temperature (°C)
SCOScale Conjugate Gradient V_{AC} Inverter voltage (V)SGDStochastic Gradient Descent V_{AC} Inverter voltage (V)SNNShallow Neural Network V_{MPP} AC side voltage (V)SVMSupport Vector Machine V_{load} Load voltage (V)t-SNEt-Distributed Stochastic Neighbor Embedding V_{OC} Open circuit voltage (V)WNNWavelet neural network V_{WIND} Wind speed (m/s) d_{WIND} Wind direction	SA	Simulated Allifeating	V	Output voltage (V)
SOD Stornastic Gradient Descent Inc. Velocity SNN Shallow Neural Network Velocity Velocity SVM Support Vector Machine Velocity Load voltage (V) t-SNE t-Distributed Stochastic Neighbor Embedding Voc Open circuit voltage (V) WNN Wavelet neural network VR Voltage ratio (%) Wund Wind speed (m/s) dwind direction	SCO	Scaled Conjugate Gradient	V_{AC}	Inverter voltage (V)
SNN Snahow Neural Network Value SVM Support Vector Machine Vload Load voltage (V) t-SNE t-Distributed Stochastic Neighbor Embedding Voc Open circuit voltage (V) WNN Wavelet neural network VR Voltage ratio (%) WunD Wind speed (m/s) dwind Wind direction	SUD	Stochastic Gradient Descent	V _{MPP}	AC side voltage (V)
SVMSupport Vector Machine I_{IOM} I_{IO	SININ	Snahow Neural Network	Vload	Load voltage (V)
t-SNEt-Distributed Stochastic Neighbor Embedding VR Specific Medge (V)WNNWavelet neural network VR Voltage ratio (%) v_{WIND} Wind speed (m/s) d_{WIND} Wind direction	SVM	Support Vector Machine	Voc	Open circuit voltage (V)
WNNWavelet neural network VR Voluge fails (w) v_{WIND} Wind speed (m/s) d_{WIND} Wind direction	t-SNE	t-Distributed Stochastic Neighbor Embedding	VR	Voltage ratio (%)
d_{WIND} Wind direction	WNN	Wavelet neural network	VWW	Wind speed (m/s)
			dwini	Wind direction

MLTs applied for FDD consist of various methods with distinctive principles and structures. The most common ones include Artificial Neural Network (ANN) [10], Fuzzy Logic (FL) [11], Support Vector Machine (SVM) [12], *k*-Nearest Neighbor algorithm (*k*NN) [13] and Decision Tree (DT) [14]-based techniques (including random forest (RF) [15]). Through keyword research¹ and the subsequent content verification in common publishers or research platforms (e.g., Science Direct, IEEE Xplore, Google Scholar, Research gate), the number of reported publications on PV FDD from 2009 to July 2020, for different types of MLTs are summarized and presented in Fig. 1.

¹ Setting of keywords for different MLTs: 'Photovoltaic' +'fault' or 'defect' or 'detection' or 'diagnosis' +technique name ('neural network'/'fuzzy logic'/'support vector machine' /'kNN' /'decision tree'/'random forest')



Fig. 1. Evolution of reported applications of MLTs for PV FDD

It can be observed that ANN technique has drawn more research interest during the last decade. All the applications differ in various aspects e.g. input data, data pre-processing, ANN type and structure (*Shallow Neural Network* (SNN) and *Deep Neural Network* (DNN) [16]²), parameter configuration, hybrid application and performance. Despite this abundant literature, there is no analysis and comparison of the applications of ANN for PV FDD. This paper is an attempt to fill this gap by doing a review of the papers published from 2009 to July 2020.

As a hierarchical model, one neural network (NN) generally includes one input layer, several hidden layers, and one output layer. Each layer is composed of several connected units (named neurons), each one associated with an activation function. It operates as parallelized processors to deal with complex systems [17]. ANN has various merits, like an excellent approximation of nonlinear function, fast decision making, no restriction on the normality or independence of input [17][18]. Thus, ANN has also been widely exploited in other PV domains [19], including solar radiation prediction [20], MPP tracking [21], solar energy system modeling [18], PV system sizing [22], and performance prediction of solar collector system [23].

This paper is interested in carrying out a literature review to answer the following questions regarding the use of ANN for PV FDD:

- How ANN techniques are integrated in the PV FDD?
- What types of PV faults are detectable using ANN-based techniques?
- What are the performance of these techniques when applied for PV FDD?
- What are the challenges and prospects that ANN would face for PV health monitoring?

The contribution of this paper is reflected in:

- 1) Applications of ANN for PV FDD are, to our best knowledge, firstly summarized in detail based on the type of neural networks: shallow, deep, and hybridized. For each type of application, their pros and limitations have been identified.
- 2) The common trends for the selection and the configuration of one ANN model when using 1-dimension (1D) or 2-dimension (2D) PV data or when targeting at different types of PV faults have been highlighted.
- 3) Four reported public PV databases, including both 1D data or 2D images, are identified from the literature and summarized.
- 4) Common challenges (e.g. the model configuration, availability of public database) and common prospects (e.g. the candidate models, feature transformation between 1D and 2D, real-time health monitoring) have also been highlighted.

The remainder of this paper is structured as follows: Section 2 presents a systematic review of the application of SNNs, DNNs and hybridized methods for PV FDD, where the key issues like model configuration, targeted fault, performance are all detailed and analyzed. Then, based on the aforementioned four questions, section 3 discusses the reviewed cases, and some common challenges and prospects are also highlighted. Section 4 concludes the

 $^{^2}$ SNN and DNN are the 2 categories of ANN, which are distinguished according to the model's depth, i.e., the number of hidden layers. However, it should be noted that this number of layers is a relative notion that principally depends on the models to be compared [16]. Hereafter, based on an overall analysis, we set 3 hidden layers as the bound, so as to facilitate the presentation and performance comparison presented in the next section.

paper.

2. Application of ANN for PV FDD

This section presents an insight into the various applications of ANN for PV FDD by separating the adopted models into three main groups, SNN, DNN and hybridized neural network (NN).

2.1. Application of SNN for PV FDD

Two categories of SNN applications are considered in this subsection, i.e., direct FDD (end-to-end type, where the SNNs output straightforward the fault type) and indirect FDD (where the output data of SNN models need further interpretation to identify the fault type).

2.1.1. Direct FDD

In the literature, various types of SNN models have been applied for direct FDD such as *Multilayer Perceptron neural network* (MLP) [24], *Radial basis function neural network* (RBF) [25], *Probabilistic neural network* (PNN) [26], *Extension neural network* (ENN) [27], *Extreme learning machine* (ELM) [28], *Elman neural network* (Elman NN) [29], and *Wavelet neural network* (WNN) [30].

In most cases, different factors (like the network structure, the number of parameters *Np* (neuron weights and bias), input/output (I/O) setting, activation function, tuning algorithm, PV technology and scale) have been taken into account to reach the best-expected performance. These applications, sorted by model type, are presented in Table 1 followed by a discussion.

Year	ANN type,	Amo	unt of da	ta	I/O setting		Activation	PV techno.	FDD Accuracy	Target Fault	Notes
& Ref	Structure & Number o parameters	Train f	Validate	Test	Input	Output	function	& scale			
2009 [31]	MLP 5-9-8 <i>Np</i> =139	NC (simu)	-	NC (simu)	• 5 failure mode	s• 8 causes	• <i>tanh</i> (hidden layer) • <i>logsig</i> (output layer)	NC, PV array	100% (average)	 Overheating Power loss Driven failure Abnormal voltage Abnormal meter 	• Input data normalized to [-1,1]
2014 [32]	MLP 3-4-3 <i>Np</i> =34	200 (<i>exp</i>)	-	4 (<i>exp</i>)	• T _M • V _{MPP} (modu) • I _{MPP} (modu)	• 3 faults (by 3 binary codes)	• <i>tanh</i> (hidden layer)	sc-Si, JHX100M, 1×72 PV string (3.9kWp)	90% (average)	Cell crackPSAging & SC module	
2015 [33]	MLP 4-11-4 <i>Np</i> =107	1600 (simu)	-	400 (simu)	• G • T _A • V _{MPP} (array) • I _{MPP} (array)	• Healthy • 3 faults (by 4 binary codes)	• NC	NC, PV array	91.94% (average) 100% (Healthy) 97.95% (Aging) 78.69% (SC) 100% (PS)	AgingPSSC module	Trained by Levenberg- Marquardt (LM) back propagation (BP) [24] algorithm [70]
2016 [34]	MLP 4-NC-3 <i>Np</i> NC	992 (simu)	-	NC (<i>exp</i>)	• I _{MPP} (array) • V _{MPP} (array) • I _{SC} (array) • V _{OC} (array)	Healthy2 faults	NC	NC, PV array	30% (1 SC module) 85% (2 or more SC modules) ~ 100% (Aging, Rs>4Ω)	• SC module • Aging	
2016 [35]	MLP 2-20-1 Np=83	7819 (simu)	-	50 (simu)	• $\Delta P(string)$ • $\Delta I_{SC}(string)$	• PS	NC	NC, 1×16 PV string	Training MSE: 0.058	• PS (exist or not)	
	MLP 2-NC-1 Np NC	12495 (simu)	-	50 (simu)	• ΔP (string) • P_{MPP} (string)	• PS factor	NC		Training MSE: 0.067	• PS (with shading factor)	
	MLP 1-NC-1 <i>Np</i> NC	28512 (simu)	-	10 (simu)	• PS factor	• Shaded module number	NC		Training MSE: 0.788	• PS (with number of shaded modules)	
2016 [36]	MLP 3-13-13-1 Np=251 RBF 3-49-4 Np=399	620 (simu)	-	155 (simu)	• R _{Voc} (array) • R _{I-MPP} (array) • R _{V-MPP} (array)	• 4 faults	• <i>logsig</i> (hidden layer)	mc-Si, 1×4 PV string (480Wp)	90.3% (average) 68.4% (average)	Cell/diode /module • Shunted • SC • Inversed • Connection resistance fault	• Trained by LM BP algorithm
2017 [37]	MLP 2-8-8-1 <i>Np</i> =107	600 (simu)	200 (simu)	200 (simu)	• G • I _{MPP} (array)	• <i>C</i> _{<i>I</i>}	• <i>logsig</i> (hidden layer)	sc-Si, Isofoton, 2×8 PV array	NC	1 SC module4 SC modules	• Fault type co- determined by <i>C_I</i> and <i>C_V</i>

Table 1 Details of PV FDD research using direct SNN

					• T _M • V _{MPP} (array)	• <i>Cv</i>		(1.7kWp)		Faulty string	• Trained by LM BP algorithm
2017 [38]	MLP 6-7-12-1 <i>Np</i> =164	NC (<i>exp</i>)	-	NC (<i>exp</i>)	• G • T _M • V _{OC} (modu) • I _{SC} (modu) • V _{MPP} (modu) • I _{MPP} (modu)	• 4 faults	NC	sc-Si, BP-MSX120, 4×18 PV array (8.6Wp)	79.86% (average)	Cell/diode/module • Shunted • SC • Inversed • Connection resistance fault	
	MLP 6-7-11-1 Np=155					• 3 faults			90.79% (average)	PS & BPD as • OC • Inversed • Shunted	
2017 [39]	MLP 2-10-3 Np=65	70% (simu)	-	30% (simu)	 <i>V_{MPP}</i>(string) <i>I_{MPP}</i>(string) 	 5 faults (by 3 binary codes) 	 logsig (hidden layer) purelin (output layer) 	NC, 1×3 PV string	NC	• 1 or 2 modules inversed PS (3 levels)	• Trained by LM BP algorithm
2018 [40]	MLP 6-25-4 <i>Np</i> =285	1397 (<i>exp</i>)	-	394 (<i>exp</i>)	 V_{MPP} (string) I_{MPP} (string) V_{load} I_{load} V_b (battery) I_b (battery) 	Healthy3 faults	• tanh (hidden layer) • logsig (output layer)	mc-Si, 1×2 PV string (180Wp)	97.4% (average)	• SC module • OC module • SC battery	• Input data normalized to [-1,1]
2019 [41]	MLP 7-33-6 <i>Np</i> =475	28800 (simu)	-	4800 (simu)	• G • T _A • V _{MPP} (array) • I _{MPP} (string1, string 2) • V _{AC} (inverter)	Healthy5 faults	NC	mc-Si, 2×8 PV array (5.3kWp)	99.7% 7(average)	 PS Aging SC module OC string Inverter fault 	• Compared and outperforms DT (accu: 89.9%), kNN (82.5%) and SVM (98.6%)
2019 [42]	MLP 6-35-1 <i>Np</i> =287	80% (<i>exp</i>)	10% (<i>exp</i>)	10% (<i>exp</i>)	• G • T_A • $VWIND$ • $dWIND$ • $Humidity$ • $Painfall$	• Soiling rate	 <i>tanh</i> (hidden layer) <i>purelin</i> (output layer) 	NC, PV module	R ² =92.8% (fitting rate)	• Soiling	• Input data normalized to [0.1, 0.9]
2020 [43]	MLP 5-10-16 <i>Np</i> =241	4368 (simu)	936 (simu)	936 (simu)	• G • T_M • $V_{MPP}(array)$ • $I_{MPP}(array)$ • $P_{MPP}(array)$	• 16 faults	 tanh (hidden layer) logsig (output layer) 	2 types (sc-Si and thin film) 9×7 PV array (9.1kWp)	99.6% ,(average)	SCOCMismatchMulti faults	• Scaled Conjugate Gradient (SCG) [44] algorithm is adopted
2020 [45]	MLP 2-NC-2 <i>Np</i> NC	NC (exp)	-	NC (exp)	Signal strength indicator of 2 antennas	• Distance between antennas to AF	NC	NC, PV simulator (2.7kWp)	Planar location error<0.2m (within a range of 4m)	• AF	 Data augmented Bayesian regularized
2020 [46]	MLP 8-5-1 <i>Np</i> =59	1200 in total (simu)	n		• G • T _M (average) • V _{MPP} (array) • I _{MPP} (array) • P _{MPP} (array) • FF (array) • I _{SC} (array) • V _{OC} (array)	• 6 faults	• tanh (hidden layer)	NC, 6×7 PV array (3.5kWp)	99.9% ((average)	 PS (2 types) SC module LLF BPD SC Temperature non-uniformity 	 Input data normalized to [0, 1] Compared with DT (accu: 95.9%), RF (96.6%)
2018 [47]	RBF 2-5-5-5 <i>Np</i> =77	4536 (<i>exp</i>)	648 (<i>exp</i>)	1296 (<i>exp</i>)	 PR (string) VR (string) 	• 5 faults	NC	mc-Si, SMT6(60), 1×5 PV	77.7% (average)	 Only PS 1 to 4 faulty modules without PS 	• Input data normalized to [- \$1,1]
	RBF 2-7-7-9 <i>Np</i> =151					• 9 faults		(1.1kWp)	92.1% (average)	 Only PS 1 to 4 faulty modules without PS 1 to 4 faulty modules with PS 	S
2020 [48]	RBF 2-10-1 Np=43 MLP 2-10-10-1 Np=153	97200 (<i>exp</i>)	in total		• G • P _{MPP} (string)	Healthy9 faults	NC	mc-Si, SMT6(60), 1×10 PV string (2.2kWp)	98.6% (average) 98.9% (average)	• OC module	• Input data normalized to [0, 1]
2015 [49]	PNN 4-4-1 <i>Np</i> =49	160 (simu)	-	340 (simu)	• G • T _A • V _{MPP} (array) • I _{MPP} (array)	Healthy3 faults	NC	mc-Si, TSM- 290PC14, 5×20 PV array (20kWr)	98.53% (average) 100% (Healthy) 97.6% (OC50) 96.5% (OC75) 100% (LE5)	• OC (2 types) • LLF	• OC50/75 means 50% /75% or less PV modules are OC
2017 [50]	PNN 4-4-2-1	2224 (simu)	-	736 (simu)	• G • T _M	• Healthy • Faulty	NC	sc-Si, Isofoton,	100% (LLF) 100%	 3 SC modules 10 SC modules	• For fault detection

	Np=37	2224 (simu)	NC (<i>exp</i>)	• V _{MPP} (array) • I _{MPP} (array)			2×15 PV array	82.3%	• 1 OC string	
	PNN 4-4-3-1 <i>Np</i> =43	1668 (simu) 1668	552 (simu) NC	• G • T_M • $V_{MPP}(array)$	• 3 faults		(9.5kWp)	100% 98.2%		• For fault diagnosis
		(simu)	(exp)	• I _{MPP} (array)				/		
2019 [51]	PNN 2-2-5-1 <i>Np</i> =29	400 - (<i>exp</i>)	500 (<i>exp</i>)	 <i>V_{MPP}(array)</i> <i>I_{MPP}(array)</i> 	Healthy4 faults	NC	mc-Si, 4×3 PV array (2.9kWp)	97% 7(average)	SC moduleOC stringLLFMulti faults	• Input data normalized by STC value
2020 [52]	PNN 7-8-8-3 <i>Np</i> =170	3000 - (<i>exp</i>)	600 (<i>exp</i>)	• G • T _M (average) • V _{MPP} (string1) • V _{MPP} (string2) • I _{MPP} (string2) • Weather	Healthy2 faults	 <i>ReLU</i> (hidden layer) <i>softmax</i> (output layer) 	NC, 2×3 PV array (1.8kWp)	100% /(average)	• LLF • OC string	 Use Adam as optimizer <i>k</i>-fold [53] validation Input data normalized
2010 [54]	ENN 4-10 <i>Np</i> =54 MLP 4-9-10 <i>Np</i> =149	1995 - (simu)	1995 (simu)	 <i>P_{MPP} (array)</i> <i>V_{MPP} (array)</i> <i>I_{MPP} (array)</i> <i>V_{OC} (array)</i> 	Healthy9 faults	• NC	sc-Si, NT-R5E3E, 2×9 PV array (3.2kWp)	100% (average) /93.3% (average)	• 1 to 3 module faults in 1 or 2 string	
2014 [55]	WNN 4-12-5 Np=129 MLP 4-12-5 Nn=129	400 - (<i>exp</i>)	100 (<i>exp</i>)	 Voc(array) I_{SC}(array) V_{MPP}(array) I_{MPP}(array) 	Healthy4 faults	• sigmoid (output layer)	sc-Si, PV array	96% (average) 79% (average)	• SC • OC • PS • Aging	• Use Gaussian function for hidden layer
2018 [56]	Elman NN 8-18-4 <i>Np</i> =246	3600 - (<i>exp</i>)	800 (<i>exp</i>)	• G • T _A • V _{In} • I _{in} • V _{load} • I _{load} • V _{MPP} (array) • I _{MPP} (array)	Healthy3 faults	• NC	NC, 4×2 mini PV array (40.3Wp)	99.5% (average)	• PS • OC string • Total shading	

('NC' in all columns represents non-communicated information; ' N_1 -... N_i -... N_L ' in 'ANN type & structure' column denotes the structure of model, i.e., N_i neurons in i^{th} layer; '(*simu*) ' and '(*exp*) ' in 'Amount of data' column denotes the data obtained from simulation or experimental test, respectively; '*modu*', '*string*' or '*array*' in 'I/O setting' column represents the electrical data measured at module, string or array level, respectively; ' $a \times b'$ in 'PV techno and scale' column denotes a parallel strings with b modules connected in series)

Focusing on the four questions proposed in the introduction, the applications displayed in Table 1 are now analyzed:

- 1) Integration of SNN in PV FDD
- *ANN type:* Ranking the selected models according to their number of uses, MLP comes first (62.5%, 15 out of 24 application cases) followed by PNN, RBF and ENN.
- *Model structure:* Relatively simple structures are most often considered, 63.6% (21 out of 33 models) with 1 hidden layer and the remaining with 2 hidden layers. The number of neurons in the hidden layer is generally less or around 10, while in some models more neurons are selected [36,41,42]. As for the number of parameters, its value is generally less than 500 in the reviewed cases.
- *Amount of data:* Total data volumes used are in the order of hundreds or thousands, and there is usually more data for training than for testing (85.7%), while the dataset for validation is relatively less adopted (4 out of 24 cases). In term of data type, simulation data is the most common one (56.5%, 35 out of 62 reported datasets for training, validation or testing) compared to field-measured data (43.5%). This is because simulation data is easier to obtain despite it may not fully represent actual data due to modeling errors and uncertainties and actual environmental conditions.
- *I/O setting:* For the input, measured features (like environmental and electrical data) are preferred to calculated ones (like the ratio of voltage or current). *V*_{MPP}, *I*_{MPP}, *G*, *T*_M are the most common ones. The selection of features depends on the target fault and PV plant scale, i.e., module or array level. For the output, some cases (like in [32,33]) use the combination binary output values of each neuron to determine the fault type. In some cases, authors export the feature values that correspond directly either to the fault type (like in

[38,50]) or to the fault severity (like in [35,42]), while the others do not specify.

- Activation function: Only in 11 out of 24 cases, the activation function used is specified. In the hidden layer, non-linear functions (like *tanh* and *logsig*) are commonly adopted, which permits the learning of complex relationship. As for the output layer, linear functions (like *pureline*, softmax) are preferred, which allows the multiple outputs for fault classification.
- *PV technology and scale:* Almost all PV devices tested are in crystalline silicon technology, if specified. This corresponds well to its representation in terms of installed capacity worldwide. Regarding the scale of the platform under test, string or array level are the most common types (23 out of 24 cases), while the module level is less investigated. The reported power rating varies from 40Wp to 29kWp.

2) Detectable faults

Among the targeted PV faults, short circuit (SC), partial shading (PS) and abnormal aging are the most studied ones. The particularity of these faults is their significant impact on the electrical features. Other faults like soiling, line-line fault (LLF), and failures in components on the DC side are relatively less investigated.

3) Performance

Generally, diagnosis accuracy is higher than 90%. However, it should be noted that comparison of performance between different research results is complex due to the difference in the database, model configuration and fault severities (like the cases in [49,50]). Nevertheless, in some applications, the applied model is compared on the same benchmark with either other types of ANN, or other MLTs. In these cases, the proposed ANNs have been demonstrated outperforming other ANNs or MLTs.

4) Limitations and prospects

In some cases, redundancy is found in the input feature setting, like the simultaneous use of V_{MPP} , I_{MPP} and P_{MPP} . Besides, some cases focus on limited fault types, even only one type, which is unsuitable for field application to deal with various unknown faults. However, encouragingly, some SNNs, especially MLP, have proven their efficiency (> 90%) to diagnose various faults for different PV platforms with different scales. These models are promising, as they look suitable for almost all the common PV electrical faults, and can be applied in real-time health monitoring.

The use of field-measured data should be encouraged, particularly for high-scale PV platforms, which are now very common. However, where the amount of faulty data is limited, simulation data could also be adopted. However, they should be as close as possible to the data measured in the field, taking into account the uncertainties and actual measurement conditions. Also, the scope of the faults to be addressed should be broadened towards soiling, line-line fault, and faults in power electronics device.

2.1.2. Indirect FDD

Regarding the indirect applications of SNNs (i.e., output features need further interpretation for fault identification), few researches have been reported. The typical ones are presented in Table 2.

Year	ANN type,	Amount of data		I/O setting		Follow-up	PV techno	FDD	Target Fault	Notes	
& Ref.	Structure & Number of parameters	Train	Validate	Test	Input	Output	- analysis	& scale	accuracy		
2011 [57]	MLP 4-10-6 <i>Np</i> =120	30 (simu)	-	NC (simu)	• G • T _M • V _{MPP} (array) • I _{MPP} (array)	• 6 voltages	Use a proposed topology to analyse the 6 voltages	sc-Si, SM-55, 3×2 PV array (330Wp)	99.9%	• SC module (with localization)	• Number of models equals the SC cases
2015 [58]	MLP 2-15-15-1 <i>Np</i> =303	134 (simu)	17 (simu)	17 (simu)	• G • T _M	• P _{predicted}	Compare the predicted <i>P</i> with measured one	Silero Triex U300, PV array (3.6kWp)	100%	 PS OC string MPPT failure	
2016 [59]	MLP 2-7-12-2 Np=145	2100 (<i>exp</i>)	-	900 (<i>exp</i>)	• G • T _M	 <i>I</i>_{predicted} <i>V</i>_{predicted} 	Compare the predicted <i>I</i> , <i>V</i> with measured ones	mc-Si, BPSX150, PV module (150Wp)	NC	• PS (failure degree could be quantified)	• Input data normalized to [-1,1]

Table 2 Details on research using indirect FDD

2018	MLP	70% -	30%	• G	 Ppredicted 	Compare the	NC,	90%	 Inverter fault
[60]	2-10-1	(exp)	(exp)	• <i>T</i> _M		predicted P with	PV array		
	Np=43					measured one	(6.2MWp)		

('NC' in all columns represents non-communicated information; ' N_1 -... N_L ' in 'ANN type & structure' column denotes the structure of model, i.e., N_i neurons in i^{th} layer; '(*simu*)' and '(*exp*)' in 'Amount of data' column denotes the data obtained from simulation or field-measurement, respectively. '*array*' in 'I/O setting' column represents the electrical data measured in array level; ' $a \times b$ ' in 'PV techno & scale' column denotes *a* parallel string with *b* modules connected in series.)

Based on Table 2, the following analysis can be conducted:

1) Integration of SNN in PV FDD

As in the previous section, MLP is still the favorite model. Similar to the prediction of PV performance [23], environmental data is used as input to predict PV electrical features that are analyzed for fault identification.

2) Detectable faults

Since all the model outputs are the electrical features, it is accordingly the faults that introduce a significant impact on the electrical features that are mainly addressed, like OC and PS.

3) Performance

The number of studies is limited compared to the direct ones, but all the reported accuracy is similarly higher than 90%.

4) Limitations and prospects

These indirect applications need an additional diagnosis module to analyze the output features. Furthermore, among these schemes, a comparison of the predicted features with the measured ones is the most common type. However, this kind of analysis could be fully realized inside one ANN by adding the measured features as inputs as it has been already done like in [37,46,52]. Therefore, the capabilities of the ANN should be fully exploited instead of complexifying the methodology.

2.2. Application of DNN for PV FDD

The Deep NN (DNN) applied for PV FDD has two main types, Convolutional Neural Network (CNN) and Deep Belief Network (DBN) [61]. Regarding the CNNs, various well-designed structures have been practiced, such as LeNet [62], GoogLeNet [63], VGG [64], R-CNN [65], ResNet [66], AlexNet [67], Attention U-Net [68], YOLO [69]. Compared to SNN models, DNNs mainly differ in the model depth, and input data type. For the input, instead of 1-dimensional (1D) features (e.g., electrical or environmental features), DNNs deal with 2-dimensional (2D) ones, which include PV images, generated graphs or matrix.

In this section, the application of DNNs using PV image data is firstly presented. Then, the DNNs handling other types of 2D data will be investigated. At the end of each part, the applications will be discussed in the light of the four questions raised in the introduction.

2.2.1. DNNs using PV image data

The 2D PV data for DNNs consists of visual (Vis.), electroluminescence (EL) or thermal infrared (IR) images, as listed in Table 3. For each application, the type, structure, input type and size, pre-processing method, data partitioning and the targeted PV fault will be taken into account. All this information is summarized in Table 4 with the unfolded hierarchical structure of three examples of DNNs illustrated in Fig. 2.

Vis. images		EL images		IR images		
Cell level	Module level	Cell level	Module level	Cell level	Module level	Array level
[70]	[71]	[72]	[73]	(]icm [74]	[75]	

Table 3 Typical PV images used in DNNs for PV FDD



Fig. 2 Examples of CNN structures adopted for PV FDD: (a) LeNet-5 [77] (low number of layers and low number of parameters), (b) Li et al. scheme [71] (low number of layers and high number of parameters), (c) VGG-19 [72] (high number of layers and high number of parameters).

Table 4 Application of DNN models using PV image data

	11				U	0						
Year & ref.	Model, No. o layers &	f Input setti	ng	Data augmentation	Amount n	of data	l		Output setting	FDD accuracy	Target fault	Notes
	Number of parameters	Type& Size	e Scope		Original	Train	Validate	Test				
2018 [77]	Adapted LeNet-5, 6 layers, <i>Np</i> =1.1M	EL images (100×100 pixels)	PV cell	 Brightness adjustment Adding blurring Rotation 	-	5120 (aug)	-	1000 (aug)	Healthy4 faults	98.4% (average)	Cell crack in forr • Linear • Cross • Flaky • Broken	n: • Trained by Nesterov Accelerated Gradient (NAG) algorithm [78]
2018 [79]	LeNet, 7 layers, <i>Np</i> =0.06M	EL images (NC)	PV cell	-	658	600 (orig)	48 (orig)	10 (orig)	• Healthy • 1 fault	99% (average)	• Cell crack	Trained by Stochastic Gradient Descent (SGD) algorithm [80] Compared and outperforms GoogleNet V1 (accu: 98%)
2018 [81]	VGG-16, 21 layers, <i>Np</i> =134.2M	IR images (224×224 pixels)	PV array	 Rotation Flip	3336	5190 (<i>aug</i>)	-	1298 (aug)	HealthyDefective	75% (best case)	• Damaged module (fault type not specified)	 Images captured by UAV Images manually- labeled Impact of data balance discussed

2018 [82]	Adapted VGG-16, 21 layers, <i>Np</i> =0.38M	EL images (120×120 pixels)	PV cell	 Flip Rotation Translation Cropping	98280	90% (aug)	-	10% (aug)	HealthyDefective	92.3% (balanced accu rate)	• Damaged cell (different levels crack)	• Impact of oversampling and augmentation discussed
2019 [72]	Adapted VGG-19, 24 layers, Np=34.9M	EL images (300×300 pixels)	PV cell	 Rotation Translation Flip	2624	196800 (aug)	-	656 (orig)	HealthyDefective	86.6% (for sc-Si images) 86.1% (for mc-Si images)	• Damaged cell (microcrack, insulation fault,) connection fault, solder failure)	 Images labeled by experts Blurry images are not excluded from dataset
2019 [84]	Mobilenet 28 layers, Np=4.2M	IR image (224×224 pixels)	sPV module	FlipRotation	798	NC (<i>aug</i>), (<i>orig</i> = 638)	-	NC (<i>aug</i>) (<i>orig</i> = 160)	Healthy4 faults	89.5%(average)	• Module hotspot (4 shapes of module hotspot)	Public dataset [83] Compared and outperforms VGG- 16 (accu: 85.8%)
2018 [85]	Deep SolarEye (based on ResNet), Np=2.0M	Visible images $(192 \times 192$ pixels) +G, time	PV module	 Rotation Flip	NC	27537 (aug)	-	18217 (aug)	• Soiling	97.8% (binary classification)	• Soiling (type, impact and location)	• Cleaning suggestion for soiling could also be determined
2018 [86]	DBN, 4 layers, <i>Np=</i> 4.7M	EL images (64×64 pixels)	PV cell	-	220	200 (orig)	-	20 (orig)	Healthy1 fault	NC	• Cell crack	
2019 [87]	Fast RCNN, 28 layers, <i>Np</i> NC	IR images (NC)	PV array	-	110	83 (orig)	-	27 (orig)	HealthyHot spot	99.7%	• Hot spot	 Images captured by UAV camera Pre-trained VGG- 16 adopted to
2020 [76]	Fast RCNN, 13 layers, Np NC	IR images (640×534 pixels)	PV array	-	900	800 (orig)	-	100 (orig)	HealthyHot spot	99.02% 99.42% (healthy) 91.67% (hot spot)	• Hot spot	 Extract feature map Images captured by UAV camera Localization error of hot spot is 0.86m
2020 [88]	Fast RCNN +RCNN (2 channels) Np NC	EL images (5232× 2720 pixels)	PV module)	-	1461	861 (orig)	-	600 (orig)	• 3 faults	98.3%(overall) 97.5% (Crack) 99% (Broken) 98.5% (Unsoldered)	CrackBrokenUnsoldered	• Fast RCNN is based on VGG-19, RCNN based on ResNet-101
2020 [89]	Attention U-net (34 layers) Np=8.1M	EL images (512×512 pixels)	PV cell	 Flip Shift Rotation	828	NC (<i>aug</i>), (<i>orig</i> = 620)		NC (<i>aug</i>) (<i>orig</i> = 208)	HealthyDefective	(dustaine) 100% (average)	• Cracks • Finger interruption	• Impact of loss function and combination of networks discussed
2020 [90]	YOLOv3, 53 layers, <i>Np</i> NC	Visible images	PV module	-	5400	4320 (orig)	-	1080 (orig)	HealthySoiling	96.3% (average)	• Soiling (bird drop, leaves)	• Compared with Mask R-CNN (92.2%)
2018 [91]	Proposed CNN, 27 layers, Np=101.2M	Vis. images (256×256 pixels)	PV cell	-	21245	15996 (orig)	-	4249 (orig)	 Healthy 6 cell defects 	94.3% (average)	• Damaged cell (broken gates, paste spot, dirty cell, thick lines, scratches, and	• Impact of CNN structure, image size, training methods discussed • CNN of
2019 [71]	Proposed CNN, 9 layers, <i>Np</i> =51.7M	Visible images (224×224 pixels)	PV module	-	8400	5880 (orig)	1680 (orig)	840 (orig)	• Healthy • 5 faults	97.9% (average) 98.9% (healthy) 100% (delamination) 98.2% (soiling) 96.1% (gridline corrosion) 95.7% (snail trail) 98.5% (discoloration)	 Delamination Soiling Gridline corrosion Snail trail Discoloration 	multispectral type • Input includes manually or UAV- captured images and generated faulty images • Setting of layers discussed and visualized by <i>t</i> - stochastic neighbor embedding (<i>t</i> -SNE)
2019 [92]	Proposed CNN, 9 layers, <i>Np</i> =2.5M	EL images (100×100 pixels)	PV cell	FlipRotationCropping	2624	80% (aug)	-	20% (aug)	HealthyDefective	93.02%	• Damaged cell (microcrack, insulation fault, connection fault, solder failure)	Same dataset used in [72] Layer setting discussed Impact of augmentation discussed
2019 [73]	Proposed CNN, 5 layers, Np=0.2M	EL images (50×50 pixels)	PV cell	FlipRotation	3550	11360 (aug)	-	710 (orig)	Healthy2 faults	99.7% (average) 100% (healthy) 100% (crack) 92% (corrosion)	Cell crackCorrosion	Impact of input size discussed Compared with SVM (accu =99.4%) and RF (97.5%) and outperforms

2020 [93]	Proposed CNN, 9 layers, Np=12.9M	EL images (224×224 pixels)	PV cell	• GAN-based model operation	1800	6400 (<i>aug</i>)	1600 (<i>aug</i>)	600 (orig)	Healhty3 faults	83% (average) 84% (healthy) 83% (break) 82% (micro-crack) 81% (Finger- interruption)	• Cell crack (3 types)	• Compared and outperforms VGG- 16 (accu: 66%), ResNet50 (67%) • Impact of depth, kernel size discussed
2020 [75]	Proposed CNN, 9 layers, Np=6.8M	IR images (100×100 pixels)	PV module	FlipRotationCropping	893	80% (<i>aug</i>)	-	20% (aug)	HealthyDefective	99.23%	Damaged module (failed interconnection, glass breakage, crack, failed /resistive soldering bonds)	 Images are from IR camera and internet Model pretrained by EL images

('NC' in all columns represents non-communicated information; $(a \times b)$ ' in 'Type & Size' refers to the size of images in pixels; (*orig*)' and '(*aug*)' in 'Amount of data' column denotes original or augmented data, respectively; The layer number indicated in 'Model' column only refers to the sum of all the inner layers)

Based on Table 4, the applications of DNNs using 2D PV image data are analyzed from the following aspects:

- 1) Integration of DNN in PV FDD
- Model type and structure: CNN models are the most common ones, which may be due to its popularity in image processing and pattern recognition in recent years. Among the applied CNN models, 12 out of 19 are based on the entire or partial structure of mature models (like LeNet and VGG in Fig. 2 (a)(c)), while the remaining six are thoroughly redesigned (like Fig. 2 (b)). As for the structure, the majority of DNNs are more complicated than SNN ones from both model depth and the number of parameters. However, it should be noted that more layers do not necessarily lead to higher Np, which can be observed from the models in Fig. 2 (b) and (c). Np mainly depends on the sizes of fully connected layers and the kernel, which are determined by the structure and vary from case to case.
- *Input setting*: For the origins of the images, indirect images (collected by EL or IR devices) are preferred to visual ones. EL images are the most adopted (11 use cases) as they may embed more fault information. Regarding the scope, cell level images are the most adopted (10 cases), while those at module level (6 cases) and at array level (3 cases) are relatively less investigated.
- *Data augmentation*: It is often practiced when the original dataset is not large enough or to increase the model generalization capability. In the reviewed cases, more than half (11 cases) implements this technique, with usually rotation and flip.
- 2) Detectable faults

At the cell level, cracking in various forms is the most frequently examined defect. At the module and network level, hot spots, delamination, soiling and interconnect failures are generally covered. A common feature of these faults is their marked presence in the adopted images. This allows the various DNNs, which are competent in pattern recognition, to identify them.

3) Performance

Overall, 13 out of 19 cases have achieved classification accuracy higher than 90%. Similarly, due to the diversity in various aspects for most applications, no further quantified global conclusion can be drawn. However, in some cases, based on the same benchmark, the proposed model has exhibited higher performance compared to other DNNs or MLTs.

4) Limitations and prospects

It is noted that more than half of the reported applications can only do binary classification, i.e., identify healthy or faulty condition. In some works, where both binary and multi-class classifications (more than 1 fault type) are conducted, the multi-class FDD accuracy is found lower than that of binary classification. This, in a sense, reflects the difficulty in precise PV faults diagnosis using image data. Besides, some models are highly complex, which could increase the computational expense. Thus, it is suggested to develop CNN model with appropriate architecture like in [73,92] to reduce unnecessary complexity. It is noteworthy that authors in [72,92] have used identical public PV image dataset [83]. Then, the comparison of different models and performance is made possible. Regarding the real-time application in large-scale power plants, DNNs

also show some potential, especially via UAV-captured aerial images. However, the automatic detection of PV panels and subsequent segmentation is still a tedious task. Although some research has been dedicated to this problem [94], the robustness and precision still require further reinforcement through more field tests.

2.2.2. DNNs using other 2D data

In addition to PV images data, DNN models for PV FDD also process graphs or data matrix generated from 1-D features as shown in Fig. 3. For example, Lu et al. [95] and Manohar et al. [96] extract graphs from sequential V and I data. Chen et al. [97] combine I-V curve data with G and T_M to form up a 40×4 feature matrix. Similar I-V curve-based approaches are also applied in [98,99]. Besides, Aziz et al. adopted Continuous Wavelet Transform (CWT) [100] to generate scalograms (2-D graphs) from environmental and array electrical parameters. A similar approach is also employed in [101]. The details of these applications are presented in Table 5.



Fig. 3 Examples of other 2D input features for DNN: (a) array *I* and *V* time-series graph [95], (b) synthetic matrix [97], (c) current-generated graphs [101], (d) 1-D features-generated scalograms [102]

Year Model, No & Ref of layers &	Model, No.	I/O setting		Amount o	Amount of data			FDD accuracy	Target	Note
& Ref	of layers & Number of parameters	Input	Output	Train	Validate	Test	— & scale		fault	
2018 [96]	SAE-DNN, Np NC	AC side I and V time-series graph	Healthy6 faults	2812 (simu)	-	1208 (simu)	NC, 3×4 PV array	100% (average)	• PS • LLF (5 types)	• Compared and outperforms SVM (accu: 99.2%), DT (99.3%), MLP (97.1%)
2019 [95]	Proposed CNN, 20 layers, Np NC	Array I and V time series graph, 299×299 pixels	Healthy4 faults	981 (<i>exp</i>)	-	419 (<i>exp</i>)	sc-Si, GL-100 3×6 PV array (1.8kWp)	99.5% (average) 99.7% (Healthy) 99.2% (SC) 98.4% (LLF) 99.9% (OC)	• LLF • SC module • OC string (2 types)	• Results obtained from 20 random tests
2019 [97]	ResNet, 18 layers, Np=1863	Matrix (40×4) based on array I-V curve and T_M , G	Healthy8 faults	15834 (simu)	1858 (simu)	7545 (simu)	sc-Si, GL-100 3×6 PV array (1.8kWp)	99.98% (average) 100% (Healthy, SC, PS, OC) 99.89% (Aging)	• OC string • PS (3 types) • Aging (2 types)	• Unbalanced samples for each case
				1870 (<i>exp</i>)	215 (<i>exp</i>)	897 (exp)	(98.1% (average) 100% (Healthy, SC) 96.68% (PS) 95.45% (OC) 95.81% (Aging)	• 1 or 2 SC module in 1 string	
2020 [98]	Proposed CNN+ Residual- gated	Matrix based on array I-V curve and <i>T_M</i> , <i>G</i>	Healthy10 faults	792 (simu)	264 (simu)	264 (simu)	sc-Si, 1×13 PV array (3.4kWp)	100% (average)	• PS (2 types) • Aging • Hybrid	• Impact of data missing, and anti-inference discussed
	recurrent unit, 7 layers, <i>Np</i> NC			1136 (<i>exp</i>)	379 (exp)	377 (exp)		98.4% (average)	fault (6 types)	
2020 [99]	Proposed CNN, 5 layers, <i>Np</i> NC	Matrix extracted from I-V curve (82×4)	Healthy3 faults	356 (<i>exp</i>)	-	90 (<i>exp</i>)	mc-Si, 2×12 PV array	99.8% (average)	• PS • Crack • Gridline fault	• Compared with multi-headed NN (99.3%)
2019 [101]	Proposed GAN+CNN, 14 layers, Np NC	Graphs generated from array <i>I</i> , 20×20 pixels	Healthy1 fault	24000 (<i>exp</i>)		6000 (<i>exp</i>)	sc-Si, PV array (1.5kWp)	98.5% (average) 99.3% (Healthy) 97.7% (AF)	• AF	 Domain adaptation applied Tested in real time FDD

Table 5 Application details of DNN models using other 2D data

2020 [102]	AlexNet (transferred), 7 layers, <i>Np</i> =58M	Generated scalograms, 227 × 227 pixels	Healthy5 faults	2419 (simu)	-	1037 (simu)	NC, 5×3 PV array (735Wp)	Noiseless condition: 74.6% (average) Noisy condition (noise power level of -3dB): 73.2% (average)	• AF • LLF • OC string • PS (2 types)	• Impact of training sample size and noise discussed
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 $(`(a \times b)`$ in 'Input' column refers to the size of images in pixels; '(simu)' and '(exp)' in 'Amount of data' column denotes the data obtained from simulation or experimental test, respectively; ' $a \times b$ ' in 'PV techno and scale' column denotes *a* parallel strings with *b* modules connected in series.)

Similarly, these applications of DNNs using other 2D data are examined from the following perspectives:

1) Integration of DNN in PV FDD

In these cases, 1D features are transformed directly (like using time-series graphs) or indirectly (via specific transformation methods) to 2D features. Since these features are not real PV images, data augmentation is not generally performed.

2) Detectable faults

The common target faults are PS, OC, LLF and AF. As the inputs are still based on the electrical or environmental 1D features, these faults are similar to the ones detected by SNNs.

3) Performance

Four out of seven cases achieved an accuracy of more than 95%, which is comparatively higher than DNNs using image data (90%). The reason behind may be fault feature separability is higher with internal variables of parameters rather than image data.

4) Limitations and prospects

Low effective information ratio is observed in some cases [95,97]. Especially in [95], the time-series graphs of current or voltage contain a large area of white zone (as shown in Fig. 3 (a)), which contributes to increase the size of the DNN input features. This problem is eased in [101,102] by adopting specific transformation techniques. The FDD schemes based on transformation from 1D to 2D have been developed to benefit from the considerable experience in image processing, with the expectation to improve the diagnosis performance. However, these schemes still require further validation and comparison with the ones using the same original 1D data and with other techniques, like the SNNs as mentioned earlier that generally have lower complexity

2.3. Hybridization of ANN for PV FDD

In order to enhance the ANN performance, several researchers have combined ANN with other techniques for different objectives, like:

- Extraction or pre-processing of input features,
- Improvement of ANN algorithm,
- Optimization of ANN parameters,
- Post-processing of output features.

According to these specific objectives, the applications of the hybridized techniques are summarized in Table 6.

Table 6 Applications of hybridized ANN for PV FDD

Aim of	Year	ANN	Integrated techno.	Amount	of data	I/O setting		PV techno	. Target faults	FDD Accuracy	Notes
hybrid	& Ref.	category,		Train	Test	Input	Output	& scale			
usage		model type,									
		structure,									
		No. of paras	6								
Improve	2015	SNN,	Fuzzy logic	32400	10800	• G	 Healthy 	NC,	• PS	86% (average)	 k-Folds technique
ANN	[103]	LAPART	(ameliorate ANN	(simu)	(simu)	• T_A	• PS	PV array			is adopted for the
algorithm	1	Np NC	structure)			• I _{MPP} (modu)		(3.7kWp)			data partitioning
			5	5760 1441	1441	• $P_{MPP}(modu)$				100% (average)	
				(exp)	(exp)	• VWIND					

l	2017 [104]	SNN, MLP (4-12-7) Np=155	Particle swarm optimization (PSO) [105] (improve the global search ability)	150 (simu)	60 (simu)	 Isc (array) Voc (array) P_{MPP} (array) V_{MPP} (array) 	 Healthy 6 faults 	NC, 3×4 PV array (252Wp)	PSAgingTemperature anomaly	93.3% (average)	 Compared with no PSO MLP (accu: 86.7%) Impact of hidden layer neuron number discussed
	2018 [106]	SNN, MLP (6-8-7) Np=125	Ada-boost classifier [107] (boost MLP performance)	1800 (<i>exp</i>)	784 (<i>exp</i>)	• G • T _A • V _{MPP} (array) • I _{MPP} (string 1-3)	 Healthy 6 faults 	sc-Si, GL-100 3×6 PV array (1.8kWp)	 PS (2 types) OC string (2 types) SC module (2 types) 	97.7% (average)	• Compared with no ada-boost MLP (accu: 96.6%)
Optimize 2 parameter	2015 [108]	SNN, MLP (2-24-24-8) Np=874	Genetic algorithm (GA) [109] (determine the number of neurons)	NC (simu)	NC (simu)	• V (modu) • I (modu)	Healthy7 faults	NC, PV module	 PS SC module OC module Aging Charger fault Battery fault 	97.7% (average) 98.6% (Healthy) 96.6% (SC) 97.5% (OC) 97.6% (PS) 98.2% (Aging) 98.9% (Charger) 96.6% (Battery)	• Results under condition T_A =33 °C, G=380 W/m ²
l	2017 [110]	SNN, KELM (7-NC-5) Np NC	Nelder-Mead Simplex (NMS) [111] (optimize kernel parameters)	3600 (<i>simu</i>) 1875 (<i>exp</i>) 4800 (<i>simu</i> + <i>exp</i>)	1200 (simu) 625 (exp) 2500 (simu +exp)	• I _{SC} (array) • V _{OC} (array) • I _{MPP} (array) • V _{MPP} (array) • n • Rs • Ep	Healthy 4 faults	sc-Si, GL-100, 3×6 PV array (1.8kWp)	 PS Aging SC module OC string 	100% (average) 98.98% (average) 98.90% (average)	 Input data normalized by STC value n: ideality factor Rs: series resistor Ep: RMSE of parameter identification
[2017 [112]	SNN, KELM (4-NC-4) Np NC	Simulated Annealing (SA) [113] (optimize model parameters)	600 (simu)	400 (simu)	• n • C _R • I _{ph} • fval	Healthy3 faults	sc-Si, SM55, 3×6 PV array (990Wp)	• PS • Aging • SC module	93.55% (Average) 99.73% (Healthy) 91.55% (PS) 90.91% (Aging) 93.64% (SC)	• C _R : resistor coefficient • I _{ph} : photocurrent • fval: optimal fitness value
Pre- 2 process or extract features	2018 [114]	SNN, MLP (4-12-4) Np=116	Discrete wavelet transform (DWT) [115] (extract features from <i>V_{MPP}</i> , <i>I_{MPP}</i>) + Principal component analysis (PCA) (ore-process)	459 (simu)	197 (simu)	• 4 extracted principle components	Healthy3 faults	NC, PV array (3.5kWp)	• Module, inverter, converter fault (type not detailed)	98.2% (average)	• Compared with RBF NN (accu: 93.6%)
1	2018 [116]	SNN, MLP (11-18- 14) Np=493	DWT based Multi- resolution analysis (MRA) [117] (extract features from converter	7000 (simu)	1750 (simu)	• 11 signal features	14 fault locations	NC, PV array (96×17) (500kWp)	• Cable GF • Cable LLF	99.2% (Average) 99.9% (Cable GF) 97.3% (Cable LLF)	 <i>tanh</i> as activation function for hidden layer and <i>sigmoid</i> for output layer Trained by LM BP
		SNN, MLP (9-18-8) Np=341	noise signal)	4500 (simu)	1125 (simu)	• 9 signal features	8 fault locations	NC, 48×17 PV array (250Wp)	• AF • LL • Module GF	97.4% (Average) 96.5% (AF) 97.4% (LLF) 98.4% (Module GF)	algorithm
1	2018 [118]	SNN, MLP 30-23-6 Np=887	Multistate data processing (extract features from inverter current)	240 (<i>exp</i>)	105 (<i>exp</i>)	• Extracted features from inverter current	Healthy6 faults	NC, 6×26 PV array (43.7kWp)	• Inverter switch OC (6 locations)	100%	
Ĩ	2018 [119]	SNN, PNN (4-NC-12 -1)	Gaussian kernel function-based fuzzy C-means (GK-FCM) [120] (label faulty data)	492 (<i>exp</i>)	984 (<i>exp</i>)	 V_{OC} (array) I_{SC} (array) V_{MPP} (array) I_{MPP} (array) 	Healthy 11 faults	mc-Si, JKM245p, 3×13PV array (9.6kWp)	 2,4 or 6 SC modules in 1 string 1 or 2 OC string Aging (R_s=2, 4 or 6 Ω) 2,4 or 6 PS module in 1 string 	92.5% (Average) 84.6% (SC) 100% (OC) 98.0% (Aging) 87.4% (PS)	• Input data normalized by STC value and <i>G</i> , <i>T</i> _M
	2019 [121]	SNN, MLP (5-12-8) Np=181	Grey level co- occurrence matrix (GLCM) [122] (extract texture features from IR images)	NC (orig)	NC (orig)	• 5 texture features from module image subregion (20×35 pixels)	• Healthy • 7 cases of temperature anomaly	NC, PV array (169.9kWp)	• Temperature anomaly (Hot)spot and other types)	92.8% (average)	 sigmoid as activation function for output layer Subregion divided from 1568 PV module IR images
l	2019 [123]	SNN, PNN (48-48-1-1) Np=2451	GLCM (extract features from microscope- captured cell images 1280×1024 pixels)	132 (orig)	240 (orig)	• 48 features	HealthyDefective	Organic PV cell	• Damaged cell (particles, bubbles, and cracks)	95.4% (average)	• Singular value decomposition (SVD) [124] is adopted to ease the dimensional greedy effect

	2019 [125]	SNN, MLP (40-100-50- 30-6) Np=7270	GLCM (extract texture features from module Vis. images)	5551 ima in total (<i>orig</i>)	ges	• 40 texture and statistical features	Healthy5 faults	mc-Si, PV module (230Wp)	• Soiling (5 levels)	96.3% (average)	• Compared and outperforms kNN (accu: 93.2%), RF (94.6%), but underperforms
	2019 [74]	DNN, GoogLeNet (21 layers) Np=6M	PCA (extract data from image sequences)	720 (orig)	720 (orig)	• Extracted cell IR image (224×224 pixels)	• 6 faults	c-Si, PV cell	 Crack Hot spot Scratch Broken edge Surface impurity Large area damage 	99.7% (average)	 SVM (97.5%) Compared and outperforms VGG- 16 (accu:99.1%), LeNet-5 (98.9%), SVM (98%) and MLP (97.3%) Pre-process techniques compared
	2019 [126]	DNN, Proposed CNN, (9 layers) Np=0.37M	Sliding window scan (extract regions from cell EL image 943×923 pixels)	NC (<i>aug</i>), (<i>orig</i> = 499)	NC (<i>aug</i>) (<i>orig</i> = 43)	• Regions (128×128 pixels)	• Defect probability of regions	NC, PV cell	• Defective cell	88.4% (average)	• 4 types of CNN structure tested
	2019 [127]	DNN, ResNet (50 layers)	Denoising CNN (DnCNN) [128] (extract soiling features)	3520 (<i>aug</i>)	880 (<i>aug</i>)	• Extracted dust layers from visible module images (244×244 pixels)	 Soiling rate 	mc-Si, CSUN260- 60P, PV module (260Wp)	• Soiling	F1: 90% RMSE: 0.69	 Images augmented by rotation and flip Original image amount: 550 Compared and outperforms other depth of ResNet
SS	2018 [129]	DNN, VGG-16 (21 layers)	SVM (classify the features extracted from pretrained model)	2400 (<i>aug</i>)	600 (<i>aug</i>)	• Visible cell images (224×224 pixels)	• Feature vector of 4090 dimension	NC, 5PV array	 Delamination Discoloration Glass breakage Soiling Snail tracks 	90.2% (Binary classification) 78.9% (Delamination) 77.3% (Discoloration) 76.9% (Breakage) 84.4% (Soiling) 77.8% (Snail tracks)	 Best results obtained on the model pre-trained by ImageNet Images captured by UAV drone
	2019 [130]	DNN, Proposed CNN, 9 layers, Np=25.7M	SVM (classify the features extracted from pretrained model)	NC (aug)	NC (aug)	• Visible module images (224×224 pixels)	• Feature vector of 512 dimension	NC, PV module	 Glass breakage Delamination Soiling Corrosion Snail trail Discoloration 	98.1% (average) 100% (healthy) 96% (glass) 98% (delamination) 96% (soiling) 97% (corrosion) 98% (snail trail) 100% (discolor)	Transfer learning based on [71] Setting of transfer discussed Compared with AlexNet (accu: 85.9%), VGG16 (68%) and outperforms
	2020 [131]	DNN, VGG-16 (21 layers) Np=134.2M	Low rank matrix recovery (LRMR) [132] (decompose output features for classification)	1372 (orig)	1372 (orig)	• Vis.+EL cell images (224×224 pixels)	• Healthy • Cell crack	mc-Si, sc-Si, PV cell	• Cracks	F1 :46.8%	• VGG pre-trained on ImageNet • Same EL dataset used in [72] • Compared and outperform non LRMR (F1: 42.6%)

('NC' in all columns represents non-communicated information; ' N_1 -... N_L ' in 'ANN type & structure' column denotes the structure of model, i.e., N_i neurons in *i*th layer; '(*simu*) ' and '(*exp*) ' in 'Amount of data' column denotes the data obtained from simulation or experimental test, respectively, '*orig*' and '*aug*' denotes the used images or the images where the input features are extracted are original or augmented, respectively; '*modu*' and '*array*' in 'I/O setting' column represents the electrical data measured in module level or array level, respectively; '*a*×*b*' in 'PV techno & scale' column denotes *a* parallel strings with *b* modules connected in series.)

As it has been done for the other techniques, hybridized ANNs are analyzed in light of the questions raised in the introduction:

1) Integration of hybridized ANN in PV FDD

Postproce

• Integrated technology & usage: Among the studied hybridization applications, extraction and pre-processing of input features are the most common objectives, covering both SNN and DNN models. Using DWT for electrical signals, and GLCM to extract features from images are the typical schemes. These techniques serve to eliminate useless information and improve the quality of input, which is essential to the performance of one ANN model. Besides, some post-processing techniques are also applied, generally in DNNs, to classify high-dimension output features. In other cases, the techniques assist in mitigating the inherent limits of the ANN technique, like the tricky procedure of parameter optimization, the time-consuming labelling work, and the imperfect learning algorithm.

• *ANN model*: Both SNNs (13 cases) and DNNs (6 cases) have been practiced for hybridization. Among SNNs, MLP is still the most popular. Among DNNs, CNNs with various structures are more considered. The favored model type and other aspects of the model configuration are similar to the aforementioned observations in the single applications of SNNs or DNNs.

2) Detectable faults:

When based on 1D features (i.e., before pre-processing), the typical target faults include PS, OC, SC and LLF. For those dealing with 2D features, defects at cell level and soiling fault are more investigated.

3) Performance:

Overall, the majority of applications (17 out of 19) achieve accuracy better than 90%. In some cases, the comparison showed that hybridization improves classification performance.

4) Limitations and prospects:

In some cases, the hybridization could increase the complexity of the FDD scheme. However, it is worthy to accept this cost if a significant amelioration is achieved. Therefore, the performance comparison is necessary to validate the combined techniques. However, this is not always reported. Nevertheless, globally, hybridization is promising, not only to improve the accuracy, but also to make possible the transformation of features from 2D to1D. Like in [115], 1D features extracted from 2D images are used as input. On one side, this transformation reduces the input features dimension, and, on the other side, allows the use of simple SNN for the diagnosis instead of DNN. This approach can significantly simplify the tuning and training process of the NN.

3. Discussion

For a better understanding of the previously described applications (73 cases), a discussion from a statistical perspective is presented in this section to provide an answer to each of the four questions raised in the introduction.

3.1. Which are the PV faults detectable by ANN?

All the common faults [8] are firstly presented in the form of 'PV DC-side fault tree' as in Fig. 4. It is based on 4 structural levels, i.e., PV cell, module, array and DC side level. The faults detected by the ANN technique are then summarized and marked as 'leaves' of the 'tree', where the number of studies using SNN or DNN is presented after the fault name, and the total number is expressed by the nuance of the block edge color (darker represents more studies).



Fig. 4. Statistical chart of PV faults detection using ANN techniques

Overall, the presented ANN techniques with different configurations can detect almost all the common faults on the PV system DC side. However, some faults like PID (almost eliminated thanks to technological improvement) and back-sheet adhesion loss are uncovered. This may be due to the detection's difficulty (limited input data, weak fault signature) or current little research interest in this context. From a quantitative aspect, short circuit module, partial shading, open circuit module and abnormal aging are the most studied ones because of their stronger signature and easy reproducibility in simulation or field tests.

Regarding the applied ANN methodology, almost all the permanently visible faults (cell crack, delamination, discoloration) are usually detected with DNN models. The other ones, like shading, structure failure and electrical faults, are detected with SNN models. This difference may mainly come from the characteristics of the fault. Indeed, permanently visible faults generally introduce a more significant impact on PV images data rather than on 1D data. Thus, DNN models that can conduct efficient image processing (using 2D data) are preferred while SNN models seem more suitable for the other faults (using 1D data).

3.2. What are the performance?

As we have seen previously, it is difficult to give a clear answer with regard to the various applications developed on different platforms. Nevertheless, on the basis of the results summarized in Tables 1, 2, 4, 5 and 6, some partial conclusions can be drawn:

- Most of the proposed ANNs can achieve classification accuracy higher than 90%, while in other cases, the relatively less satisfying performance is supposed mainly due to the low separability of the adopted input features or the improper type or structure of the developed models.
- Hybrid models generally perform better than the original ones with the average reported improvement of accuracy as 3.9% relying on the integrated techniques.
- In some applications, using the same benchmark, the proposed ANN outperforms other MLTs (like DT, RF, SVM, etc.) with the average reported improvement of accuracy as 3.8%. However, it should be noted that this shows only a general trend and does not necessarily mean that the ANN always outperforms other MLTs. These results are valid in the cases presented and depend on how these candidate techniques are developed and parameterized.

3.3. How is ANN integrated in PV FDD?

3.3.1. Source of dataset

The input 1D data is obtained at 57.6% from simulation and 42.4% from field measures among the reported training, validation and test dataset. The popularity of simulation data may be owing to its good controllability of test conditions (e.g., independent control of G and T) and low acquisition cost. However, the approximation to real PV conditions is restricted. On the opposite, despite field data reflects the operational condition, its wide application is still limited because of weak condition controllability (weather conditions, season, etc.) and measurement issues (accessibility, sensors). Therefore, the selection of data sources is a trade-off among all the aforementioned factors. Whereas, it is still recommended to use at least the field data as the test dataset to evaluate model performance under real conditions.

2D data includes PV image, generated graph or matrix. With regard to image dataset, except very few cases that employ generated PV faulty images, the majority of the adopted dataset is captured in the field. In recent years, taking benefit from the rapid development of drone technology, UAV with an embedded camera has been widely used for remote inspection of PV power plants. Abundant EL or IR images have been gathered. Nevertheless, the quantity of the original dataset is always inadequate to fulfill a fine-tuning and may consequently introduce the underfitting problem (i.e., a model cannot capture any trend [133]). A common solution is to perform rotation, flip, adding blurry, adjusting illumination or other operations to enrich the original dataset. These transformations are found convenient and efficient to enhance the generalization ability of the DNNs. As for the generated graph or matrix that are based on 1D features, the first results are promising but still require further validation of the necessity of the 1D-to-2D FDD scheme.

3.3.2. Data pre-processing

Since 1D values lie usually in different ranges, e.g. irradiations range from 0 to 1300 W/m^2 while the temperature varies from -10 to 80 °C (in the reviewed applications), they are usually normalized before being introduced into the ANN. The results show a significant decrease in the iteration process, especially when the features are centered and standardized.

For 2D data, the unification of image size and digital pre-processing (like graying operation, RGB separation) are also necessary.

3.3.3. Type of data

1D data is presented in Fig. 5 (a) with 4 categories (environmental, electrical, model-calculated, and compared data (ratio between 2 parameters)) and 2D data is presented in Fig. 5 (b).



Fig. 5. ANN input data for PV FDD, (a) 1D data, (b) 2D data

For 1D data, environmental and electrical measures are the most frequent. Among single data type, V_{MPP} and I_{MPP} are the most selected ones, as they reflect the MPP changes due to various faults. *G* (specifically, plane-of-array irradiance) and T_M (backplane module temperature), which are almost always measured have gained similar acceptance because of their impact on PV performance. V_{OC} and I_{SC} are also employed but to a lesser extent probably due to the measurement difficulty when the PV system is operating. The model-calculated and compared

data are up to now less used probably due to PV model accuracy and calculation complexity for parameter extraction.

For 2D data, EL and visual images are preferred to IR and other data types as input features to DNN models. For IR technology, the cost and complexity of the equipment is still an issue, and moreover the operating point and the environmental conditions (outside temperature, wind velocity, ...) make it difficult to interpret and process the images. The other 2D data types are just beginning to be used, and their application will grow with new 1D-to-2D transformation techniques.

3.3.4. Applied ANN models

All the reported model types with their cumulative number of publications are presented in Fig. 6. It is observed that, among the various ANN types, MLP and CNN are the most popular ones. This, to a certain degree, shows their efficiency and adaptability. In the meantime, other models like RBF and PNN have also been exploited for a limited number of applications. However, it should be noted that research interest in CNN models has grown rapidly since 2017, making it possible to envisage its development in the coming years.



Fig. 6. Cumulative publications number of PV FDD using different ANN models (until July 2020)

On the other hand, it is also necessary, for each model, to keep an eye on the time gap between the theoretical development and its first application as presented in Fig. 6^3 .



Fig. 7. Theory-to-application time gaps of models in PV FDD (a) for SNN models, (b) for DNN modelsRegarding the SNN models in Fig. 7 (a), ample time gaps are observed for almost all the models. This is

³ The MLP model discussed here refers to the MLP integrated with BP learning algorithm, which was firstly reported in 1986 [24]

particularly evident for RBF, PNN and MLP with more than 20 years. However, ENN is an exception with only a 7-year time gap probably because its creator has conducted the application. This phenomenon of large theory-toapplication time gap may be due to three reasons: firstly, based on the literature [134–136], it has been observed that research on PV FDD started in the 1980s with conventional methods (power loss or I-V curve analysis); secondly, the increasing availability of data collected from PV power plant; finally the growing concern of operators to improve the energy efficiency of their plants.

As for the DNN models shown in Fig. 7 (b), large time-gaps are also identified for the LeNet and DBN models. Nevertheless, the time-gap displays a decreasing trend for the newly developed models, especially for VGG, GoogLeNet and ResNet whose applications have started in 2018. This evolution may be owing to the gradual maturity and dissemination of image processing and pattern recognition.

3.3.5. Parameter configuration

For each ANN model, there are several key configurations, the number of hidden layers, the activation function, the loss function, the learning rate, the combination of convolutional and pooling layers (for CNN), all of which are troublesome to be directly determined. Therefore, comparative studies with different settings are crucial to finding an optimal configuration, like the reported cases in [38,47,71].

Besides, since CNN models are commonly more complicated than SNN ones, there are some open-access models pre-trained with standard image datasets (like ImageNet [137]). These models could be adopted and get further trained by PV image dataset, which may save the training time and promote the PV FDD performance, as the application in [129]. However, these models, generally with complex and deep structures, may introduce unnecessary redundancy for the application to PV FDD. Consequently, under the circumstances with limited computing capability or using a large number of samples, the structure of these models should also be thoroughly re-examined.

3.3.6. Summary of applications

The three reviewed application scenarios using SNN, DNN or hybrid methods, differ in various aspects, all of which have been investigated and discussed before. Now, the key features of these scenarios are summarized and compared. The pros and cons are also presented.

Application scenarios	Common types	Common input data	Distribution of input data	Common pre- processing operations	Common target PV faults	Advantages	Disadvantages
Application of SNN models	• MLP • RBF • PNN • ENN • ELM	Electrical data Environmental data	• 57.6% cases use simulation data, 42.4% use experimental data • 92.6% electrical data are at string or array level, 7.4% are at module level	Normalization Scaling by STC value or environmental data	Electrical faults (like SC, OC, LLF) PS Aging	 Simple structure Easy access of a large number of data (simulation type) 	• Weak in processing 2D data
Application of DNN models	• CNN • ResNet • DBN	 PV image data Generated graph Synthetic matrix 	 55.6% case use augmented data, 44.4% original data 55.6% input images at cell level, 33.3% at module level, 11.1% at array level 	 Image resizing and segmentation Data augmentation 	• Permanent visible faults (like cell crack, snail trails)	 Efficient in image processing Dataset for pre-training available on the Internet Mature models available on the Internet for reference Shared weights (for CNN and ResNet) 	 Require a large number of labeled 2-D data High computational complexity Prone to gradient vanishing
Hybrid application	 For parameter optimization For pre- processing For post processing 		Depend on SNN	or DNN		 Mitigate the inherent limits of ANN technique Provide input features with richer information Ameliorate the FDD performance 	• Effort needed to realize efficient integration

Table 7 Comparison of key features of 3 scenarios of ANN for PV FDD

3.4. What are the challenges and prospects of ANN for PV FDD?

For SNNs, DNNs, and hybrid applications, their corresponding limitations and prospects have been detailed. Here, some common points will be discussed as follows:

3.4.1. Challenges

• Model configuration

Generally, the model configuration is a tough and tedious task. Various aspects like model structure (layer number, order and size), learning algorithm, loss function, activation function, need to be determined. Regarding the application in PV FDD, when using certain types of PV features and targeting specific types of faults, there should be a commonality in the best-performing models. Under these cases, instructional strategies for the model configuration are expected to be given, however, this is not available yet and thus requires further exploration.

• Public PV fault database

In the reviewed literature, the majority of the research relies on their own-developed dataset that makes the comparison of different proposed models and performance nearly impossible. A public database, containing 1D or 2D features for common PV faults and technologies, is in desperate need. This lack is particularly real for 2D image data, since it is time-consuming and expensive to collect large amounts of PV images and do the corresponding labeling work. Up to now, in the reviewed work, some shared datasets (both 1D and 2D type) are presented in Table 8. However, the amount and covered fault types still require further enrichment and integration.

Table 8	Public I	V fault	datasets
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Ref.	Data type	Amount of data	Fault type	Lien
[83]	EL images (PV cell, 300×300 pixels)	2426	• Defective cell	https://github.com/zaebayern/elpv-dataset
[73]	EL images (PV cell, 250×250 pixels)	1031	CracksCorrosion	https://osf.io/v6pwe/
[85]	Vis. Images (PV module, 192×192 pixels)	45754	Soiling	https://deep-solar-eye.github.io/
[52]	1D data (environmental and electrical parameters of PV array)	3000 sets	LLFOC string	https://github.com/benjamin2044/PV_fault_Python/t ree/master

3.4.2. Prospects

• Other candidate models to be evaluated

Considering PV FDD is an interdisciplinary issue between PV technology and health monitoring, it is essential for researchers to pay additional attention to the development of related FDD techniques. For SNNs, some classical models are still not fully explored, like various autoencoder [138] (sparse, denoising and contractive type), modular neural network [139] and many variants of recurrent neural network [140] (e.g., fully recurrent, Hopfield, bidirectional type). For DNNs, driven by the great research interest in pattern recognition and deep learning, models with new structures spring up, like EfficientNet [141], DenseNet [142], SqueezeNet [143], ShuffleNet [144], etc., all of which could be evaluated for PV FDD.

• Different types of input data

Since CNN appears as an efficient tool for image classification, it can be applied to PV images captured by other techniques (e.g., pulse thermography, lock-in thermography and UV fluorescence [142]). This method may permit the identification of more PV fault types (like PID) not covered by traditional ANN models. Besides, with feature-extraction or transformation implemented, various novel 2D-to-1D or 1D-to-2D features could be adopted.

• Hybrid methods

Although ANN techniques hold some inherent limits, hybrid methods with feature-extraction approaches, parameter-optimization methods or MLTs are likely to mitigate the problems. In addition, there are various other proved-efficient data-driven methods, e.g., T-test [145], Linear Discriminant Analysis (LDA) [146], clustering [147], which can also be combined with ANN. Hence, hybridized ANN for PV FDD would become a promising research topic.

• Real-time health monitoring

Another merit of ANN is its rapid decision making. With a well-trained model, high-precision real-time health monitoring for PV arrays is made possible. Besides, based on the monitoring results, protection functions could be enabled, like the ANN-integrated relay operation of PV microgrid in [96,101].

Experiences from other fields

ANN technique is commonly applied, not just in PV FDD, but also in the health monitoring of other systems, like for wind turbines [148], gas turbines [149], rolling bearing [150], etc. Consequently, the practice of ANN technique in these related fields, like the configuration of the model, pre- or post-processing methods, and hybridization, may provide useful experiences for the application in PV FDD.

4.Conclusion

In this paper, a literature overview for the application of Artificial neural networks for PV fault detection and diagnosis is performed. Artificial neural networks have been proved efficient in the detection and diagnosis task for nearly all the common PV faults, including both the electrical faults (reflected in 1-dimension features, commonly dealt with shallow neural networks) and permanent visible faults (reflected in 2-dimension features, commonly dealt with deep neural networks). The reported classification success rate is higher than 90%. Besides, in some cases, performance comparisons with other machine learning techniques have shown the superiority of the proposed model. As for the model type, *Multi-layer perception neural network* and *Convolutional neural network* are identified as the most commonly adopted shallow and deep neural network, respectively. They can be adopted as starting models for future research.

Based on the detailed analyses of use cases, some challenges were identified. The most common ones are the difficulty in configuring the model, and the low availability of an open database on PV system failures. The latter is particularly challenging for deep neural network, as the number of faulty PV images is important for learning. It is therefore recommended that research groups or operators share as much as possible their databases with 1 and 2-dimension characteristics for healthy and different fault conditions. This database cannot only improve the generalizability of the proposed models, but will also facilitate comparisons.

Also, some prospects have been highlighted. On one side, with the rapid development of deep learning and PV technologies, more types of models and potential input features (including transformed features between 1 and 2 dimension) deserve to be explored. On the other side, the hybridization with other techniques and the application in online health monitoring are worth developing. This review is expected to be useful both for first users and experts in the hot topic of PV plant health monitoring.

5. Acknowledgment

The authors would like to thank the China Scholarship Council for Ph.D. funding.

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